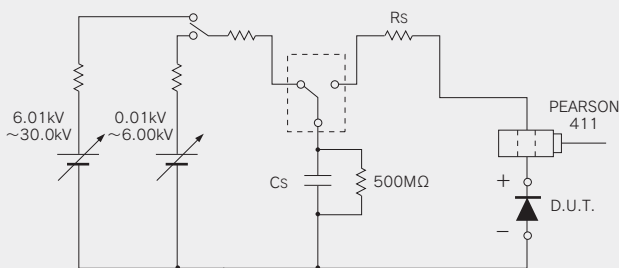


ESD TEST SYSTEM 高速サージ破壊試験装置

CV-30KB 30KV

- CV-30KB has been designed to perform ESD test by forcing at high voltage 30kV, then the tester guarantees device's deterioration by leak current measurement or breakdown voltage measurement. Leak voltage is measured before and after forcing surge pulse and check deterioration by the change of device.
- CV-30KBは超高電圧30kVでのESD試験を行い、その後のリーク電流測定や耐圧測定で素子の劣化状態を確認するテスターです。リーク測定はサージパルス印加前と印加後に測定し、変化の推移より劣化の有無を確認します。

Fundamental Test Circuit



MODEL	CV-30KB
ESD TEST	
CAPACITANCE	100pF, 200pF, 300pF, 500pF, 1000pF, 2000pF
RESISTOR	0Ω, 100Ω, 150Ω, 200Ω, 300Ω, 500Ω, 1kΩ, 1.5kΩ
PULSE VOLTAGE	0.01kV~6.00kV(10V STEP) 6.01kV~30.0kV(100V STEP)
PULSE	1~99
INTERVAL TIME	1.0sec~9.9sec
IL TEST	
VL(Forcing)	1V~3.00kV
IL(Detect)	0.0nA~9.99mA
LIMIT GATE	0.0nA~9.99mA
VR TEST	
IR(Forcing)	10μA~9.99mA
VR(Detect)	0V~3.00kV
LIMIT GATE	0V~3.00kV
DIMENSIONS & WEIGHT	
MAIN UNIT	430(W)×550(D)×245(H)…30kg
HV UNIT	430(W)×550(D)×245(H)…28kg
HEAD BOX	430(W)×550(D)×340(H)…26kg